

KIRK HANDSET TESTS

All KIRK Handsets have undergone and passed the following tests:

- Cyclic humidity (IEC 60068-2-30)
- Life time (heat) (IEC 60068-2-2)
- Life time (cold) (IEC 60068-2-1)
- Life time (heat/cold) (IEC 60068-2-14 Na)
- Salt fog (3040 & 40xx: Mil-std 810E509.3.1 / 5020: IEC 60068-2-11 -IEC 60068-2-3)
- Vibration (IEC 60068-2-6)
- Life time (ringer) (IEC 60068-2-2)
- ESD (static electricity)
- Life time (keyboard)
- Life time (head set montage)
- Drop Test (150 cm)
- Bump Test (IEC 60068-2-29)
- Effect use (standby)
- Effect use (active)

In addition KIRK 40xx and KIRK 5020 have also undergone and passed the following tests:

- Life time storage temp (warm)
- Life time storage temp (cold)

Additional KIRK 3040 Handset Test:

- Dust test (mil-std-810E 510.3)

Additional KIRK 4040 Handset Tests:

- Enclosure Protection (dripping): IEC 60529 (2001-02), Ed. 2.1, IPx2
- Enclosure Protection (splashing): IEC 60529 (2001-02), Ed. 2.1, IPx4
- Enclosure Protection (dust-protected): IEC 60529 (2001-02), Ed. 2.1., IP5x

Additional KIRK 4080 Handset Tests:

- Enclosure Protection (dripping): IEC 60529 (2001-02), Ed. 2.1, IPx2
- Enclosure Protection (splashing): IEC 60529 (2001-02), Ed 2.1, IPx4
- Enclosure Protection (dust-tight): IEC 60529 (2001-02), Ed. 2.1, IP6x
- ATEX approved: II2G II3D T60°C EEx ib IIC T3, ATEX EN 50014 & EN 50020
- IEC approved: Ex ib IIC T3, IEC Standards IEC 60079-0 & IEC 60079-11